0.64 to 8.3x



### LM98722

# 3 Channel, 16-Bit, 45 MSPS Analog Front End with LVDS/ **CMOS Output, Integrated CCD/CIS Sensor Timing Generator and Spread Spectrum Clock Generation**

#### **General Description**

The LM98722 is a fully integrated, high performance 16-Bit, 45 MSPS signal processing solution for digital color copiers, scanners, and other image processing applications. Highspeed signal throughput is achieved with an innovative architecture utilizing Correlated Double Sampling (CDS), typically employed with CCD arrays, or Sample and Hold (S/H) inputs (for higher speed CCD or CMOS image sensors). The signal paths utilize 8 bit Programmable Gain Amplifiers (PGA), a +/-9-Bit offset correction DAC and independently controlled Digital Black Level correction loops for each input. The PGA and offset DAC are programmed independently allowing unique values of gain and offset for each of the three analog inputs. The signals are then routed to a 45MHz high performance analog-to-digital converter (ADC). The fully differential processing channel shows exceptional noise immunity, having a very low noise floor of -74dB. The 16-bit ADC has excellent dynamic performance making the LM98722 transparent in the image reproduction chain.

A very flexible integrated Spread Spectrum Clock Generation (SSCG) modulator is included to assist with EM compliance and reduce system costs.

#### **Applications**

- Multi-Function Peripherals
- High-speed Currency/Check Scanners
- Flatbed or Handheld Color Scanners
- **High-speed Document Scanners**

#### **Features**

- LVDS/CMOS Outputs
- LVDS/CMOS/Crystal Clock Source with PLL Multiplication
- Integrated Flexible Spread Spectrum Clock Generation
- CDS or S/H Processing for CCD or CIS sensors
- Independent Gain/Offset Correction for Each Channel
- Automatic per-Channel Gain and Offset Calibration
- Programmable Input Clamp Voltage
- Flexible CCD/CIS Sensor Timing Generator

#### **Key Specifications**

Maximum Input Level 1.2 or 2.4 Volt Modes

(both with + or - polarity option) 16-Bit

**ADC** Resolution **ADC Sampling Rate** 45 MSPS

+18/-25 LSB (typ)

Channel Sampling Rate 22.5/22.5/15 MSPS **PGA Gain Steps** 256 Steps

PGA Gain Range Analog DAC Resolution +/-9 Bits

Analog DAC Range +/-307mV or +/-614mV Digital DAC Resolution +/-6 Bits

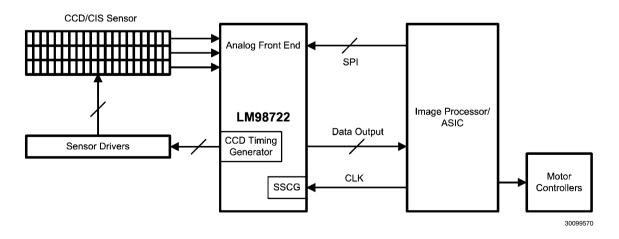
Digital DAC Range -2048 LSB to + 2016 LSB SNR -74dB (@0dB PGA Gain)

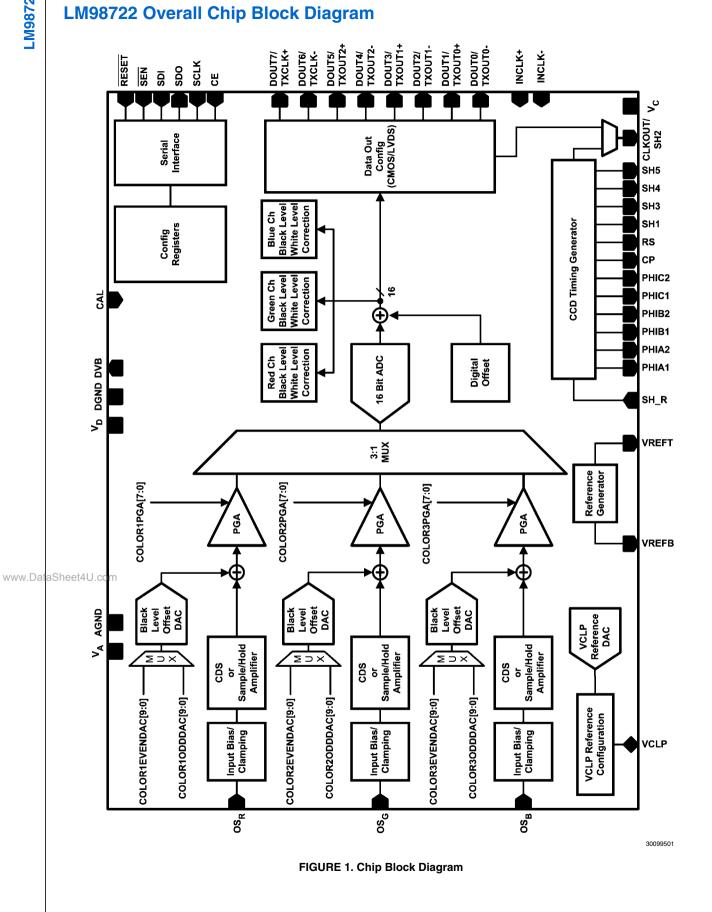
**Power Dissipation** 630mW (LVDS) Operating Temp 0 to 70°C

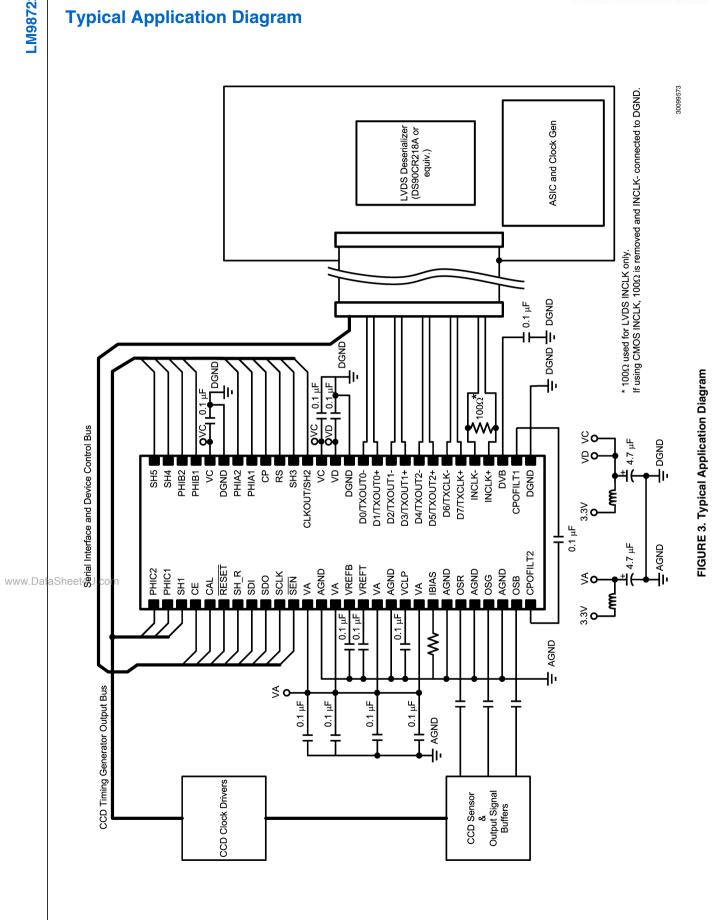
Supply Voltage 3.3V Nominal (3.0V to 3.6V range)

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## **System Block Diagram**







# **Pin Descriptions**

Pin	Name	I/O	Тур	Res		Description
1	PHIC2	0	D	PU	Configurable high speed se	nsor timing output.
2	PHIC1	0	D	PD	Configurable high speed se	nsor timing output.
3	SH1	0	D	PU	Configurable low speed sen	sor timing output.
4	CE	I	D		Chip Serial Interface Addres	ss Setting Input
					CE Level	Address
					V <sub>D</sub>	01
					Float	10
					DGND	00
5	CAL	I	D	PD	Initiate calibration sequence	. Leave unconnected or tie to DGND if unused.
6	RESET	I	D	PU	Active-low master reset. NC	when function not being used.
7	SH_R	I	D	PD	External request for an SH i	nterval.
8	SDI	I	D	PD	Serial Interface Data Input.	
9	SDO	0	D		Serial Interface Data Output	:.
10	SCLK	I	D	PD	Serial Interface shift register	clock.
11	SEN	I	D	PU	Active-low chip enable for the	ne Serial Interface.
12	V <sub>A</sub>		Р		Analog power supply. Bypas	ss voltage source with 4.7µF and pin with 0.1µF to AGND.
13	AGND		Р		Analog ground return.	
14	V <sub>A</sub>		Р		Analog power supply. Bypas	ss voltage source with 4.7µF and pin with 0.1µF to AGND.
15	VREFB	0	Α		Bottom of ADC reference. B	ypass with a 0.1µF capacitor to ground.
16	VREFT	0	Α		Top of ADC reference. Bypa	ass with a 0.1µF capacitor to ground.
17	V <sub>A</sub>		Р		Analog power supply. Bypas	ss voltage source with 4.7µF and pin with 0.1µF to AGND.
18	AGND		Р		Analog ground return.	
19	VCLP	Ю	Α		Input Clamp Voltage. Norma	illy bypassed with a 0.1μF , and a 4.7μF capacitor to AGND.
					An external reference voltaç	ge may be applied to this pin.
20	V <sub>A</sub>		Р		Analog power supply. Bypas	ss voltage source with 4.7µF and pin with 0.1µF to AGND.
21	IBIAS	0	Α		Bias setting pin. Connect a	9.0 kOhm 1% resistor to AGND.
22	AGND		Р		Analog ground return.	
23	OS <sub>R</sub>	I	Α		Analog input signal. Typical	y sensor Red output AC-coupled thru a capacitor.
24	AGND		Р		Analog ground return.	
25 <sup>WW.L</sup>	osheet4U.com	ı	Α		Analog input signal. Typical	y sensor Green output AC-coupled thru a capacitor.
26	AGND		Р		Analog ground return.	
27	OS <sub>B</sub>	I	Α		Analog input signal. Typical	y sensor Blue output AC-coupled thru a capacitor.
28	CPOFILT2		А		Charge Pump Filter Capacit CPOFILT1.	or. Bypass this supply pin with a 0.1µF capacitor to
29	DGND		Р		Digital ground return.	
30	CPOFILT1		А		Charge Pump Filter Capacit CPOFILT2.	or. Bypass this supply pin with a 0.1µF capacitor to
31	DVB	0	D		Digital Core Voltage bypass	. Not an input. Bypass with 0.1µF capacitor to DGND.
32	INCLK+	I	D			nput for LVDS clocks or CMOS clock input. CMOS clock is at DGND, otherwise clock is configured for LVDS operation.
33	INCLK-	I	D		<del>                                     </del>	for LVDS clocks, connect to DGND for CMOS clock.
34	DOUT7/ TXCLK+	0	D		<del> </del>	ut bus in CMOS Mode, LVDS Frame Clock+ in LVDS Mode.
35	DOUT6/ TXCLK-	0	D		Bit 6 of the digital video outp	ut bus in CMOS Mode, LVDS Frame Clock- in LVDS Mode.
36	DOUT5/ TXOUT2+	0	D		Bit 5 of the digital video outp	out bus in CMOS Mode, LVDS Data Out2+ in LVDS Mode.

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Pin	Name	I/O	Тур	Res	Description
37	DOUT4/	0	D		Bit 4 of the digital video output bus in CMOS Mode, LVDS Data Out2- in LVDS Mode.
	TXOUT2-				
38	DOUT3/	0	D		Bit 3 of the digital video output bus in CMOS Mode, LVDS Data Out1+ in LVDS Mode.
	TXOUT1+				
39	DOUT2/	0	D		Bit 2 of the digital video output bus in CMOS Mode, LVDS Data Out1- in LVDS Mode.
	TXOUT1-				
40	DOUT1/	0	D		Bit 1 of the digital video output bus in CMOS Mode, LVDS Data Out0+ in LVDS Mode.
	TXOUT0+				
41	DOUT0/	0	D		Bit 0 of the digital video output bus in CMOS Mode, LVDS Data Out0- in LVDS Mode.
	TXOUT0-				
42	DGND	0	D	PD	Configurable sensor control output.
43	V <sub>D</sub>		Р		Power supply for the digital circuits. Bypass this supply pin with 0.1µF capacitor. A single
				l	4.7μF capacitor should be used between the supply and the VD, VR and VC pins.
44	V <sub>C</sub>		Р		Power supply for the sensor control outputs. Bypass this supply pin with 0.1µF capacitor.
45	CLKOUT/SH2	0	D		Output clock for registering output data when using CMOS outputs, or a configurable
					low speed sensor timing output.
46	SH3	0	D		Configurable low speed sensor timing output.
47	RS	0	D		Configurable high speed sensor timing output.
48	СР	0	D		Configurable high speed sensor timing output.
49	PHIA1	0	D		Configurable high speed sensor timing output.
50	PHIA2	0	D		Configurable high speed sensor timing output.
51	DGND		Р		Digital ground return.
52	V <sub>C</sub>		Р		Power supply for the sensor control outputs.
	!				Bypass this supply pin with 0.1µF capacitor.
53	PHIB1	0	D		Configurable high speed sensor timing output.
54	PHIB2	0	D		Configurable high speed sensor timing output.
55	SH4	0	D		Configurable low speed sensor timing output.
56	SH5	0	D	†	Configurable low speed sensor timing output.
					I

 $(I=Input),\ (O=Output),\ (IO=Bi-directional),\ (P=Power),\ (D=Digital),\ (A=Analog),\ (PU=Pull\ Up\ with\ an\ internal\ resistor),\ (PD=Pull\ Down\ with\ an\ internal\ resistor).$ 

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### **Absolute Maximum Ratings (Note 1, Note**

2)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/ Distributors for availability and specifications.

Supply Voltage (VA,VR,VD,VC)	4.2V
Voltage on Any Input Pin	-0.3V to
(Not to exceed 4.2V)	(VA + 0.3V)
Voltage on Any Output Pin	-0.3V to
(execpt DVB and not to exceed 4.2V)	(VA + 0.3V)
DVB Output Pin Voltage	2.0V
Input Current at any pin other than	±25 mA
Supply Pins (Note 3)	
Package Input Current (except Supply	±50 mA

Pins) (Note 3)

Maximum Junction Temperature (TA)

Thermal Resistance ( $\theta_{JA}$ ) <66°C/W Package Dissipation at  $T_A = 25$ °C >1.89W (*Note 4*)

ESD Rating (Note 5)

Human Body Model 2500V
Machine Model 250V
Storage Temperature -65°C to +150°C

Soldering process must comply with National Semiconductor's Reflow Temperature Profile specifications. Refer to www.national.com/packaging. (Note 6)

### Operating Ratings (Note 1, Note 2)

Operating Temperature Range  $0^{\circ}\text{C} \le T_{\text{A}} \le +70^{\circ}\text{C}$ All Supply Voltage +3.0V to +3.6V

#### **Electrical Characteristics**

The following specifications apply for VA = VD = VC = 3.3V,  $C_L$  = 10pF, and  $f_{INCLK}$  = 15MHz unless otherwise specified. **Boldface limits apply for T<sub>A</sub> = T<sub>MIN</sub> to T<sub>MAX</sub>**; all other limits T<sub>A</sub> = 25°C.

150°C

Symbol	Parameter	Conditions	Min (Note 9)	Typ (Note 8)	Max ( <i>Note 9</i> )	Units
CMOS Digi	tal Input DC Specifications (RESETb,	SH_R, SCLK, SENb)				
$V_{IH}$	Logical "1" Input Voltage		2.0			V
V <sub>IL</sub>	Logical "0" Input Voltage				0.8	V
V <sub>IHYST</sub>	Logic Input Hysteresis			0.6		
I <sub>IH</sub>	Logical "1" Input Current	V <sub>IH</sub> = VD				
		RESET, SEN		100		nA
		SH_R, SCLK, SDI, CAL		65		μΑ
		CE		30		nA
I <sub>IL</sub>	Logical "0" Input Current	$V_{IL} = DGND$				
		RESETSEN		-65		μΑ
		SH_R, SCLK, SDI, CAL		-100		nA
		CE		-30		μΑ
CMOS Digi	al Output DC Specifications (SH1 to	SH5, RS, CP, PHIA, PHIB, PHI	C)		,	
V <sub>OH</sub>	Logical "1" Output Voltage	I <sub>OUT</sub> = -0.5mA	3.0			V
V <sub>OL</sub>	Logical "0" Output Voltage	I <sub>OUT</sub> = 1.6mA			0.21	V
I <sub>os</sub>	Output Short Circuit Current	V <sub>OUT</sub> = DGND		18		mA
		V <sub>OUT</sub> = VD		-25		
I <sub>oz</sub>	CMOS Output TRI-STATE Current	V <sub>OUT</sub> = DGND		20		nA
02		$V_{OUT} = VD$		-25		
CMOS Digi	al Output DC Specifications (CMOS I	Data Outputs)	· ·		Į	
V <sub>OH</sub>	Logical "1" Output Voltage	I <sub>OUT</sub> = -0.5mA		2.3		V
V <sub>OL</sub>	Logical "0" Output Voltage	I <sub>OUT</sub> = 1.6mA		0.12		V
I <sub>os</sub>	Output Short Circuit Current	V <sub>OUT</sub> = DGND		12		mA
		V <sub>OUT</sub> = VD		-14		
I <sub>OZ</sub>	CMOS Output TRI-STATE Current	V <sub>OUT</sub> = DGND		20		nA
<u> </u>		$V_{OUT} = VD$		-25		

Cumbal	Davamatar	Conditions	Min	Тур	Max	[]m!4
Symbol	Parameter	Conditions	(Note 9)	(Note 8)	(Note 9)	Units
LVDS/CMOS	Clock Receiver DC Specifications	(INCLK+ and INCLK- Pins)				
V <sub>IHL</sub>	Differential LVDS Clock	$R_L = 100\Omega$			200	mV
	High Threshold Voltage	V <sub>CM</sub> (LVDS Input Common Mode Voltage)= 1.25V				
V <sub>ILL</sub>	Differential LVDS Clock Low Threshold Voltage		-200			mV
V <sub>IHC</sub>	CMOS Clock High Threshold Voltage	INCLK- = DGND	2.0			٧
V <sub>ILC</sub>	CMOS Clock Low Threshold Voltage				0.8	٧
I <sub>IHL</sub>	CMOS Clock Input High Current			230	260	μA
I <sub>ILC</sub>	CMOS Clock Input Low Current		-135	-120		μΑ
LVDS Outpu	t DC Specifications	•			•	
V <sub>OD</sub>	Differential Output Voltage	$R_1 = 100\Omega$	280	390	490	mV
V <sub>os</sub>	LVDS Output Offset Voltage	<u> </u>	1.08	1.20	1.33	٧
I <sub>os</sub>	Output Short Circuit Current	$V_{OUT} = 0V$ , $R_L = 100\Omega$		8.5		mA
	ly Specifications	1001 11,112				
IA	VA Analog Supply Current	LVDS Output Data Format		139	162	mA
	<b>5</b>	LVDS Output Data Format (Powerdown)		3.1	4.5	mA
		CMOS Output Data Format (40 MHz)		137	161	mA
ID	VD Digital Output Driver Supply	LVDS Output Data Format		50	65	mA
	Current	LVDS Output Data Format (Powerdown)		5.5	8	mA
		CMOS Output Data Format (ATE Loading of CMOS Outputs > 50 pF) (40 MHz)		48	62	mA
IC aSheet4U.com	VC CCD Timing Generator Output Driver Supply Current	Typical sensor outputs: SH1-SH5, PHIA, PHIB, PHIC, RS, CP (ATE Loading of CMOS Outputs > 50pF)		1	4	mA
PWR	Average Power Dissipation	LVDS Output Data Format		630	736	mW
		LVDS Output Data Format (Powerdown)		28	32	mW
		CMOS Output Data Format (ATE Loading of CMOS Outputs > 50pF) (40 MHz)		600	740	mW
Input Sampl	ing Circuit Specifications					
V <sub>IN</sub>	Input Voltage Level	CDS Gain=1x, PGA Gain=1x CDS Gain=2x, PGA Gain= 1x		2.3 1.22		Vp-p

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Symbol	Parameter	Conditions	Min ( <i>Note 9</i> )	<b>Typ</b> ( <i>Note 8</i> )	Max (Note 9)	Units
I <sub>IN_SH</sub>	Sample and Hold Mode	Source Followers Off		19	25	μΑ
	Input Leakage Current	CDS Gain = 1x	(-103)	(-95)		
		$OS_X = VA (OS_X = AGND)$				
		Source Followers Off		33	50	μA
		CDS Gain = 2x	(-152)	(-141)		
		$OS_X = VA (OS_X = AGND)$				
		Source Followers On		20	250	nA
		CDS Gain = 2x	(-250)	(-50)		
		$OS_X = VA (OS_X = AGND)$				
C <sub>SH</sub>	Sample/Hold Mode Equivalent Input Capacitance	CDS Gain = 1x		2.5		pF
	Equivalent input Supusitance	CDS Gain = 2x		4		pF
ſ	CDS Mode	Source Followers Off		10	250	nA
I <sub>IN_CDS</sub>	Input Leakage Current	$OS_X = VA (OS_X = AGND)$	(-250)	(-50)	230	117
	CLPIN Switch Resistance	σοχ = νΑ (σοχ = Ασινο)	( 230)		- F F	
R <sub>CLPIN</sub>	(OS <sub>X</sub> to VCLP Node)			16	55	Ω
ICI D Dofo	rence Circuit Specifications					
OLF Reiel	·	VCI B Voltage Setting 000		0.85VA		V
	VCLP Voltage 000	VCLP Voltage Setting = 000				V
	VCLP Voltage 001	VCLP Voltage Setting = 001		0.9VA		
	VCLP Voltage 010	VCLP Voltage Setting = 010		0.95VA		V
$V_{VCLP}$	VCLP Voltage 011	VCLP Voltage Setting = 011		0.6VA		V
VOL	VCLP Voltage 100	VCLP Voltage Setting = 100		0.55VA		V
	VCLP Voltage 101	VCLP Voltage Setting = 101		0.4VA		V
	VCLP Voltage 110	VCLP Voltage Setting = 110		0.35VA		V
	VCLP Voltage 111	VCLP Voltage Setting = 111		0.15VA		V
$I_{SC}$	VCLP DAC Short Circuit Output	0001 xxxxb VCLP Config.		30		mA
	Current	Register =				
Black Leve	I Offset DAC Specifications	1			1	
	Resolution			10		Bits
	Monotonicity		Gı	uaranteed by	characteriza	tion
MANAY DataS	Offset Adjustment Range	CDS Gain = 1x				
WWW.Datao	heet4U.cm Referred to AFE Input	Minimum DAC Code = 0x000		-614		mV
		Maximum DAC Code = 0x3FF		614		
		CDS Gain = 2x				
		Minimum DAC Code = 0x000		-307		mV
		Maximum DAC Code = 0x3FF		307		
	Offset Adjustment Range	Minimum DAC Code = 0x000	-17500		-16130	LSB
	Referred to AFE Output	Maximum DAC Code = 0x3FF	+16130		+17500	
	DAC LSB Step Size	CDS Gain = 1x		1.2		mV
		Referred to AFE Output		(32)		(LSB
DNL	Differential Non-Linearity		-0.85	+0.74/ -0.37	+2.4	LSB
INL	Integral Non-Linearity		-2.5	+0.72/ -0.56	+2.5	LSB
PGA Specif	fications	l			ı	
•	Gain Resolution			8		Bits
	Monotonicity		Gi	uaranteed by	characteriza	
	Maximum Gain	CDS Gain = 1x	7.7	8.3	8.8	V/V
	Maximum Gain					

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Symbol	Parameter	Conditions	Min ( <i>Note 9</i> )	Typ ( <i>Note 8</i> )	Max ( <i>Note 9</i> )	Units
	Minimum Gain	CDS Gain = 1x	0.58	0.64	0.70	V/V
		CDS Gain = 1x	-4.7	-4.2	-3.5	dB
	PGA Function	Gain (V/V Gain (dB) = 20	, ,	77-PGA Code 0/(277-PGA (		
	Channel Matching	Minimum PGA Gain Maximum PGA Gain		3 12.7		%
ADC Specif	ications				•	
V <sub>REFT</sub>	Top of Reference			2.07		V
V <sub>REFB</sub>	Bottom of Reference			0.89		V
V <sub>REFT</sub> - V <sub>REFB</sub>	Differential Reference Voltage		1.06	1.18	1.30	V
	Overrange Output Code			65535		
	Underrange Output Code			0		
Digital Offs	et "DAC" Specifications		•		,	•
	Resolution			7		Bits
	Digital Offset DAC LSB Step Size	Referred to AFE Output		32		LSB
	Offset Adjustment Range	Min DAC Code =7b0000000		-2048		
	Referred to AFE Output	Mid DAC Code =7b1000000  Max DAC Code = 7b1111111		0 +2016		LSB
Full Channe	el Performance Specifications			-	*	-
DNL	Differential Non-Linearity	(Note 10)	-0.999	+0.8/-0.7	2.5	LSB
INL	Integral Non-Linearity	(Note 10)	-75	+18/-25	75	LSB
		Minimum PGA Gain		-76		dB
CND	Total Quitaut Naisa	(Note 10)		10	26	LSB RMS
SNR	Total Output Noise	Maximum PGA Gain		-56		dB
		(Note 10)		96		LSB RMS
	Channel to Channel Crosstalk	Mode 3		26		LCB
		Mode 2		17		LSB

# **AC Timing Specifications**

The following specifications apply for VA = VD = VC = 3.3V,  $C_L$  = 10pF, and  $f_{INCLK}$  = 15MHz unless otherwise specified. **Boldface limits apply for T<sub>A</sub> = T<sub>MIN</sub> to T<sub>MAX</sub>**; all other limits T<sub>A</sub> = 25°C.

Symbol	Parameter	Conditions	Min ( <i>Note</i> 9)	Typ (Note 8)	Max ( <i>Note 9</i> )	Units	
nput Clo	ck Timing Specifications						
		INCLK = PIXCLK	0.66		15 (Mode 3)		
		(Pixel Rate Clock)	1		22.5 (Mode 2)	MHz	
f <sub>INCLK</sub>	Input Clock Frequency	INCLK = ADCCLK	1		22.5 (Mode 1) 45 (Mode 3)		
		(ADC Rate Clock)	2		45 (Mode 2)	   MHz	
		(ABO Hato Globily	-		22.5 (Mode 1)	"""	
T <sub>dc</sub>	Input Clock Duty Cycle		40/60	50/50	60/40	%	
ull Chan	nel Latency Specifications	•				,	
	3 Channel Mode Pipeline Delay	PIXPHASE0		24			
ŧ		PIXPHASE1		23 1/2			
t <sub>LAT3</sub>		PIXPHASE2		23		T <sub>ADC</sub>	
		PIXPHASE3		22 1/2			
	2 Channel Mode Pipeline Delay	PIXPHASE0		21			
t <sub>LAT2</sub>		PIXPHASE1		20 1/2		T <sub>ADC</sub>	
		PIXPHASE2		20		ADC	
		PIXPHASE3		19 1/2			
	1 Channel Mode Pipeline Delay	PIXPHASE0		19		4	
t <sub>LAT1</sub>		PIXPHASE1		18 1/2		T <sub>ADC</sub>	
		PIXPHASE2		18		1	
) D T		PIXPHASE3		17 1/2		l	
1	ning Specifications		1			1	
t <sub>SHR_S</sub>	SH_R Setup Time			2		ns	
t <sub>SHR_H</sub>	SH_R Hold Time			2		ns	
1	tput Timing Specifications	LVDC Output	0.40	1 0 1	0.40	T ==	
TX <sub>pp0</sub>	TXCLK to Pulse Position 0  SheeTXCLK to Pulse Position 1	LVDS Output	-0.46	0	0.46	ns	
ν <b>πχ</b> <sub>pp1</sub> ata		Specifications not	2.71	3.17	3.63	ns	
TX <sub>pp2</sub>	TXCLK to Pulse Position 2	tested in production.	5.89	6.35	6.81	ns	
TX <sub>pp3</sub>	TXCLK to Pulse Position 3	Min/Max guaranteed	9.06	9.52	9.98	ns	
TX <sub>pp4</sub>	TXCLK to Pulse Position 4	by design,	12.24	12.70	13.16	ns	
TX <sub>pp5</sub>	TXCLK to Pulse Position 5	characterization and statistical	15.41	15.87	16.33	ns	
TX <sub>pp6</sub>	TXCLK to Pulse Position 6	analysis.	18.59	19.05	19.51	ns	
CMOS Ou	Itput Timing Specifications						
	CLKOUT Diging Edge to CMCC	f <sub>INCLK</sub> = 40MHz					
t <sub>CRDO</sub>	CLKOUT Rising Edge to CMOS Output Data Transition	INCLK = ADCCLK	2	6	9	ns	
	Output Data Hallstiloll	(ADC Rate Clock)					
Sorial Inte	erface Timing Specifications				<u> </u>		

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Symbol	Parameter	Conditions	Min (Note 9)	Typ (Note 8)	Max (Note 9)	Units		
f <sub>SCLK</sub>	Input Clask Fraguency	f <sub>SCLK</sub> <= f <sub>INCLK</sub> INCLK = PIXCLK (Pixel Rate Clock) Mode 3/2/1			15/22.5/22.5	MHz		
	Input Clock Frequency	$f_{SCLK} \le f_{INCLK}$ INCLK = ADCCLK (ADC Rate Clock) Mode 3/2/1			45/45/22.5	MHz		
	SCLK Duty Cycle			50/50		ns		
t <sub>IH</sub>	Input Hold Time		1.5			ns		
t <sub>IS</sub>	Input Setup Time		2.5			ns		
t <sub>SENSC</sub>	SCLK Start Time After $\overline{\text{SEN}}$ Low		1.5			ns		
t <sub>SCSEN</sub>	SEN High after last SCLK Rising Edge		2.5			ns		
t <sub>SENW</sub>	SEN Pulse Width	INCLK present INCLK stopped (Note 11, Note 12)	6 50			T <sub>INCLK</sub> ns		
t <sub>OD</sub>	Output Delay Time			11	14	ns		
t <sub>HZ</sub>	Data Output to High Z				0.5	T <sub>SCLK</sub>		

Note 1: Absolute Maximum Ratings indicate limits beyond which damage to the device may occur. Operating Ratings indicate conditions for which the device is functional, but do not guarantee specific performance limits. For guaranteed specifications and test conditions, see the Electrical Characteristics. The guaranteed specifications apply only for the test conditions listed. Some performance characteristics may degrade when the device is not operated under the listed test conditions. Operation of the device beyond the Operating Ratings is not recommended.

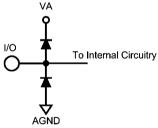
Note 2: All voltages are measured with respect to AGND = DGND = 0V, unless otherwise specified.

**Note 3:** When the input voltage  $(V_{IN})$  at any pin exceeds the power supplies  $(V_{IN} < GND \text{ or } V_{IN} > V_A \text{ or } V_D)$ , the current at that pin should be limited to 25 mA. The 50 mA maximum package input current rating limits the number of pins that can simultaneously safely exceed the power supplies with an input current of 25 mA to two.

Note 4: The maximum power dissipation must be derated at elevated temperatures and is dictated by  $T_{JMAX}$ ,  $\theta_{JA}$  and the ambient temperature,  $T_A$ . The maximum allowable power dissipation at any temperature is  $P_D = (T_{JMAX} - T_A)/\theta_{JA}$ . The values for maximum power dissipation listed above will be reached only when the device is operated in a severe fault condition (e.g. when input or output pins are driven beyond the power supply voltages, or the power supply polarity is reversed). Such conditions should always be avoided.

- Note 5: Human body model is 100 pF capacitor discharged through a 1.5 k $\Omega$  resistor. Machine model is 220 pF discharged through  $\Omega$ .
- Note 6: Reflow temperature profiles are different for lead-free and non-lead-free packages.

www.Dalash Note, 7: The analog inputs are protected as shown below. Input voltage magnitudes beyond the supply rails will not damage the device, provided the current is limited per note 3. However, input errors will be generated If the input goes above VA and below AGND.



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Note 8: Typical figures are at  $T_A = 25$ °C, and represent most likely parametric norms at the time of product characterization. The typical specifications are not guaranteed.

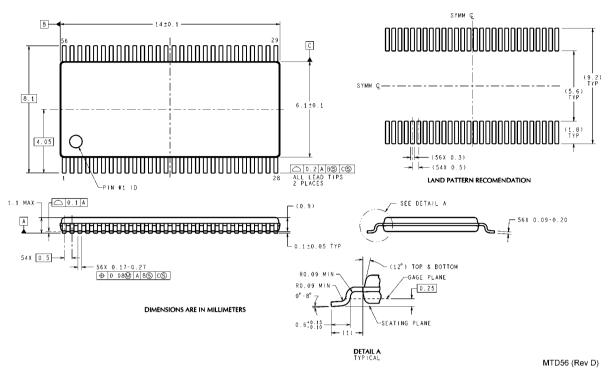
Note 9: Test limis are guaranteed to National's AOQL (Average Outgoing Quality Level).

Note 10: This parameter guaranteed by design and characterization.

Note 11: If the input INCLK is divided down to a lower internal clock rate via the PLL, the parameter t<sub>SFNW</sub> will be increased by the same factor.

 $\textbf{Note 12:} \ \ \textbf{When the Spread Spectrum Clock Generation feature is enabled, } \\ t_{SENW} \ \ \textbf{should be increased by 1.}$ 

# Physical Dimensions inches (millimeters) unless otherwise noted



56-Lead TSSOP NS Package Number MTD56

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#### **Notes**

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Voltage Reference	www.national.com/vref	Design Made Easy	www.national.com/easy		
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